

WSD30L30DN

P-Ch MOSFET

General Description

The WSD30L30DN is the highest performance trench P-ch MOSFET with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The WSD30L30DN meet the RoHS and Green Product requirement , 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

Absolute Maximum Ratings

Product Summery

BVDSS	RDSON	ID
-30V	15mΩ	-32A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

DFN3.3X3.3-8 Pin Configuration





		Rating		
Symbol	Parameter	10s	Steady State	Units
V _{DS}	Drain-Source Voltage	-	30	V
V _{GS}	Gate-Source Voltage	<u>±</u>	20	V
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ -10V ¹	-	32	А
I _D @T _C =100℃	Continuous Drain Current, V _{GS} @ -10V ¹	-	-20	
I _D @T _A =25℃	Continuous Drain Current, V _{GS} @ -10V ¹	-13	-10.5	А
I _D @T _A =70℃	Continuous Drain Current, V _{GS} @ -10V ¹	-8.7	-8.4	А
I _{DM}	Pulsed Drain Current ² -70		А	
EAS	Single Pulse Avalanche Energy ³ 49		mJ	
I _{AS}	Avalanche Current	-14		А
P _D @T _C =25℃	Total Power Dissipation ⁴	29.8		W
P _D @T _A =25℃	Total Power Dissipation ⁴	3.5	3.1	W
T _{STG}	Storage Temperature Range	-55 to 150		°C
TJ	Operating Junction Temperature Range	-55 1	-55 to 150	

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-Ambient ¹		75	°C/W
R _{0JA}	Thermal Resistance Junction-Ambient ¹ (t ≤10s)		40	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹		4.2	°C/W



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Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-30			V
$\triangle BV_{DSS} / \triangle T_J$	BV _{DSS} Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$, I_D=-1mA		-0.022		V/℃
Р		V _{GS} =-10V , I _D =-16A		15	19	
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =-4.5V , I _D =-8A		24	32	mΩ
V _{GS(th)}	Gate Threshold Voltage		-1.3	-1.8	-2.3	V
$ riangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS} = V_{DS}$, $I_D = -2500A$		4.6		mV/℃
	Drain Source Lookage Current	V_{DS} =-24V , V_{GS} =0V , T_{J} =25 $^{\circ}$ C			-1	uA
I _{DSS}	Drain-Source Leakage Current	V_{DS} =-24V , V_{GS} =0V , T _J =55 $^\circ$ C			-5	
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm20V$, $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V _{DS} =-5V , I _D =-15A		15		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		4		Ω
Qg	Total Gate Charge (-4.5V)			20	24	
Q _{gs}	Gate-Source Charge			1.1		nC
Q _{gd}	Gate-Drain Charge			7.7		
T _{d(on)}	Turn-On Delay Time	V _{DD} =-15V , V _{GS} =-10V , R _G =6Ω, I _D =-1A, RL=15Ω.		11.2		
Tr	Rise Time			10.6		
T _{d(off)}	Turn-Off Delay Time			37		ns
T _f	Fall Time			50		
Ciss	Input Capacitance	V _{DS} =-15V , V _{GS} =0V , f=1MHz		1000		
C _{oss}	Output Capacitance			220		pF
C _{rss}	Reverse Transfer Capacitance			170		

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy 5	V _{DD} =-25V , L=0.5mH , I _{AS} =-14A	40			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current ^{1,6}	$V_G = V_D = 0V$, Force Current			-14	A
I _{SM}	Pulsed Source Current ^{2,6}				-70	А
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =-2.9A , T _J =25℃			-1.2	V
t _{rr}	Reverse Recovery Time	IF=-6A,dI/dt=100A/µs , Tյ=25℃		19		nS
Qrr	Reverse Recovery Charge			10		nC

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, t<10sec.

2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%

3. The EAS data shows Max. rating . The test condition is V_{DD} =-25V, V_{GS} =-10V, L=0.5mH, I_{AS} =-14A

4.The power dissipation is limited by 150 $^\circ\!\!\mathbb{C}$ junction temperature

5. The Min. value is 100% EAS tested guarantee.

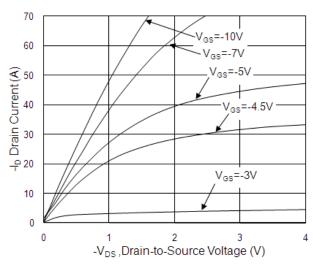
6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

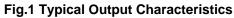


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Typical Characteristics





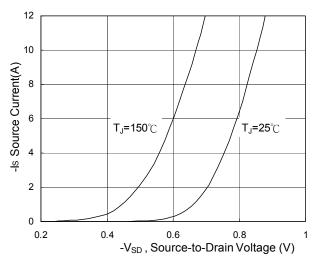
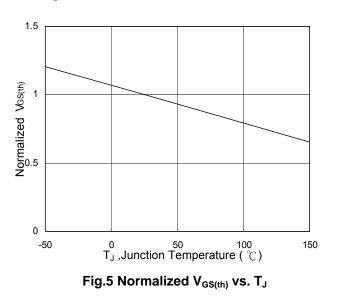


Fig.3 Forward Characteristics of Reverse



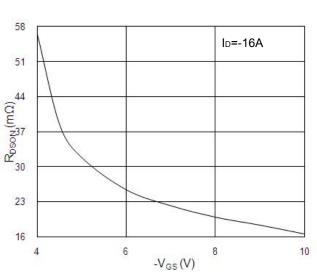
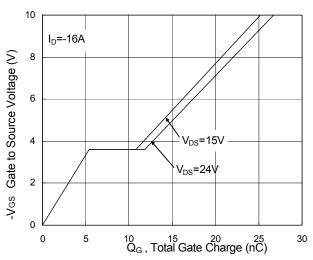
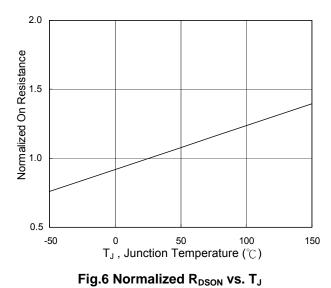
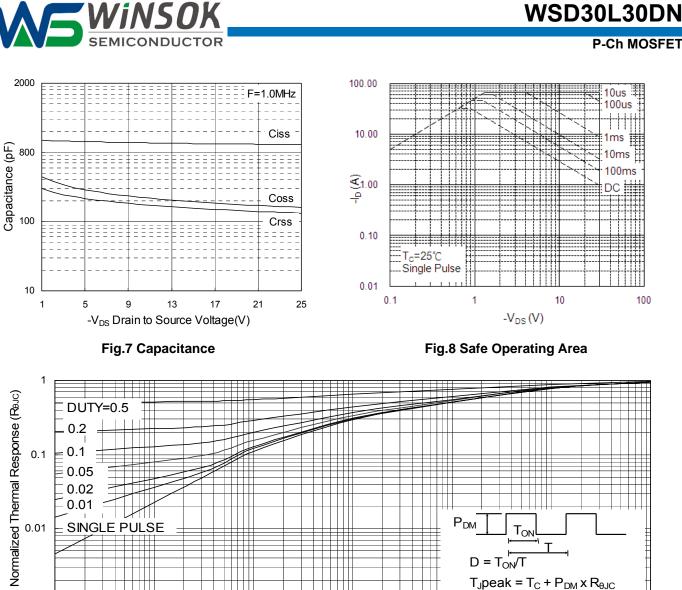


Fig.2 On-Resistance v.s Gate-Source









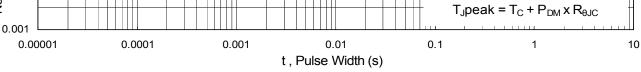
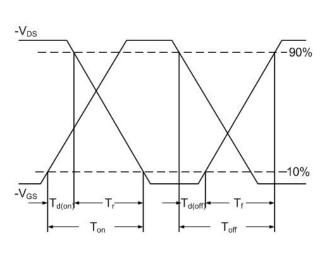
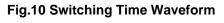


Fig.9 Normalized Maximum Transient Thermal Impedance





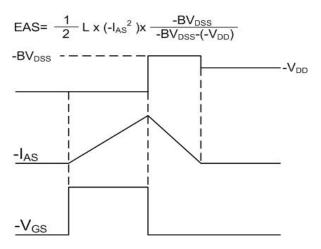


Fig.11 Unclamped Inductive Switching Waveform



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